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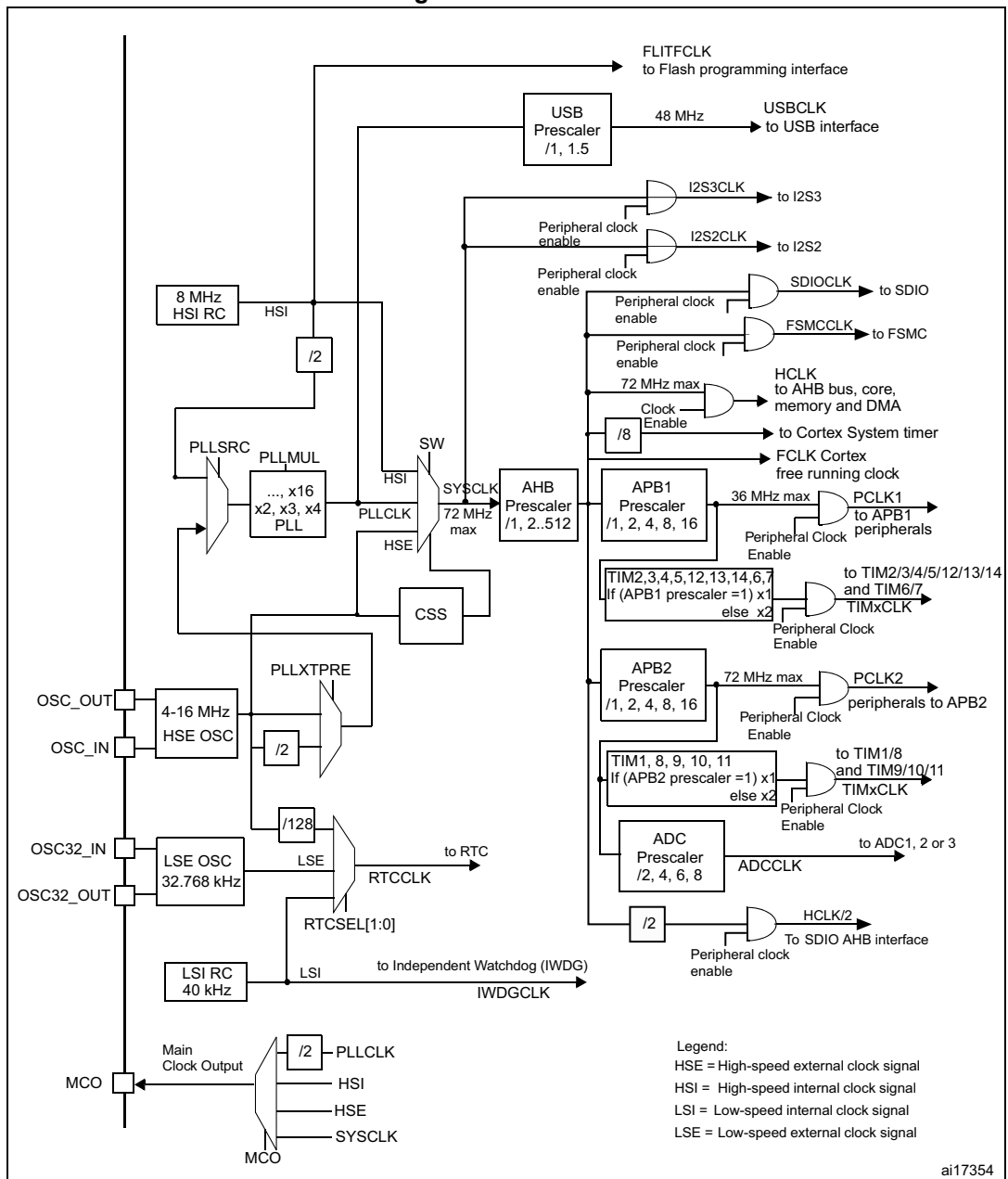
"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I ² C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, Motor Control PWM, PDR, POR, PVD, PWM, Temp Sensor, WDT
Number of I/O	112
Program Memory Size	768KB (768K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 21x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f103zft6

Figure 2. Clock tree



1. When the HSI is used as a PLL clock input, the maximum system clock frequency that can be achieved is 64 MHz.
2. For the USB function to be available, both HSE and PLL must be enabled, with the USBCLK at 48 MHz.
3. To have an ADC conversion time of 1 μ s, APB2 must be at 14 MHz, 28 MHz or 56 MHz.

The DMA can be used with the main peripherals: SPI, I²C, USART, general-purpose, basic and advanced-control timers TIMx, DAC, I²S, SDIO and ADC.

2.3.17 RTC (real-time clock) and backup registers

The RTC and the backup registers are supplied through a switch that takes power either on V_{DD} supply when present or through the V_{BAT} pin. The backup registers are forty-two 16-bit registers used to store 84 bytes of user application data when V_{DD} power is not present. They are not reset by a system or power reset, and they are not reset when the device wakes up from the Standby mode.

The real-time clock provides a set of continuously running counters which can be used with suitable software to provide a clock calendar function, and provides an alarm interrupt and a periodic interrupt. It is clocked by a 32.768 kHz external crystal, resonator or oscillator, the internal low-power RC oscillator or the high-speed external clock divided by 128. The internal low-speed RC has a typical frequency of 40 kHz. The RTC can be calibrated using an external 512 Hz output to compensate for any natural quartz deviation. The RTC features a 32-bit programmable counter for long term measurement using the Compare register to generate an alarm. A 20-bit prescaler is used for the time base clock and is by default configured to generate a time base of 1 second from a clock at 32.768 kHz.

2.3.18 Timers and watchdogs

The XL-density STM32F103xF/G performance line devices include up to two advanced-control timers, up to ten general-purpose timers, two basic timers, two watchdog timers and a SysTick timer.

[Table 4](#) compares the features of the advanced-control, general-purpose and basic timers.

Table 4. STM32F103xF and STM32F103xG timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
TIM1, TIM8	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	Yes
TIM2, TIM3, TIM4, TIM5	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	No
TIM9, TIM12	16-bit	Up	Any integer between 1 and 65536	No	2	No
TIM10, TIM11 TIM13, TIM14	16-bit	Up	Any integer between 1 and 65536	No	1	No
TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

Table 5. STM32F103xF and STM32F103xG pin definitions (continued)

Pins				Pin name	Type ⁽¹⁾	I/O level ⁽²⁾	Main function ⁽³⁾ (after reset)	Alternate functions ⁽⁴⁾	
LFBGA144	LQFP64	LQFP100	LQFP144					Default	Remap
H3	10	17	28	PC2	I/O		PC2	ADC123_IN12	-
H4	11	18	29	PC3	I/O		PC3	ADC123_IN13	-
J1	12	19	30	V _{SSA}	S		V _{SSA}	-	-
K1	-	20	31	V _{REF-}	S		V _{REF-}	-	-
L1	-	21	32	V _{REF+}	S		V _{REF+}	-	-
M1	13	22	33	V _{DDA}	S		V _{DDA}	-	-
J2	14	23	34	PA0-WKUP	I/O		PA0	WKUP/USART2_CTS ⁽⁸⁾ / ADC123_IN0 / TIM2_CH1_ETR / TIM5_CH1 / TIM8_ETR	-
K2	15	24	35	PA1	I/O		PA1	USART2_RTS ⁽⁷⁾ / ADC123_IN1 / TIM5_CH2 / TIM2_CH2 ⁽⁷⁾	-
L2	16	25	36	PA2	I/O		PA2	USART2_TX ⁽⁷⁾ / TIM5_CH3 / ADC123_IN2 / TIM9_CH1 / TIM2_CH3 ⁽⁷⁾	-
M2	17	26	37	PA3	I/O		PA3	USART2_RX ⁽⁷⁾ / TIM5_CH4 / ADC123_IN3 / TIM2_CH4 ⁽⁷⁾ / TIM9_CH2	-
G4	18	27	38	V _{SS_4}	S		V _{SS_4}	-	-
F4	19	28	39	V _{DD_4}	S		V _{DD_4}	-	-
J3	20	29	40	PA4	I/O		PA4	SPI1_NSS ⁽⁷⁾ / USART2_CK ⁽⁷⁾ / DAC_OUT1 / ADC12_IN4	-
K3	21	30	41	PA5	I/O		PA5	SPI1_SCK ⁽⁷⁾ / DAC_OUT2 / ADC12_IN5	-
L3	22	31	42	PA6	I/O		PA6	SPI1_MISO ⁽⁷⁾ / TIM8_BKIN / ADC12_IN6 / TIM3_CH1 ⁽⁷⁾ / TIM13_CH1	TIM1_BKIN
M3	23	32	43	PA7	I/O		PA7	SPI1_MOSI ⁽⁷⁾ / TIM8_CH1N / ADC12_IN7 / TIM3_CH2 ⁽⁷⁾ / TIM14_CH1	TIM1_CH1N
J4	24	33	44	PC4	I/O		PC4	ADC12_IN14	-
K4	25	34	45	PC5	I/O		PC5	ADC12_IN15	-
L4	26	35	46	PB0	I/O		PB0	ADC12_IN8 / TIM3_CH3 / TIM8_CH2N	TIM1_CH2N

Table 9. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	–65 to +150	°C
T_J	Maximum junction temperature	150	°C

5.3 Operating conditions

5.3.1 General operating conditions

Table 10. General operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
f_{HCLK}	Internal AHB clock frequency	-	0	72	MHz
f_{PCLK1}	Internal APB1 clock frequency	-	0	36	
f_{PCLK2}	Internal APB2 clock frequency	-	0	72	
V_{DD}	Standard operating voltage	-	2	3.6	V
$V_{DDA}^{(1)}$	Analog operating voltage (ADC not used)	Must be the same potential as $V_{DD}^{(2)}$	2	3.6	V
	Analog operating voltage (ADC used)		2.4	3.6	
V_{BAT}	Backup operating voltage	-	1.8	3.6	V
P_D	Power dissipation at $T_A = 85\text{ °C}$ for suffix 6 or $T_A = 105\text{ °C}$ for suffix 7 ⁽³⁾	LQFP144	-	666	mW
		LQFP100	-	434	
		LQFP64	-	444	
		LFBGA144	-	500	
T_A	Ambient temperature for 6 suffix version	Maximum power dissipation	–40	85	°C
		Low-power dissipation ⁽⁴⁾	–40	105	
	Ambient temperature for 7 suffix version	Maximum power dissipation	–40	105	°C
		Low-power dissipation ⁽⁴⁾	–40	125	
T_J	Junction temperature range	6 suffix version	–40	105	°C
		7 suffix version	–40	125	

- When the ADC is used, refer to [Table 62: ADC characteristics](#).
- It is recommended to power V_{DD} and V_{DDA} from the same source. A maximum difference of 300 mV between V_{DD} and V_{DDA} can be tolerated during power-up and operation.
- If T_A is lower, higher P_D values are allowed as long as T_J does not exceed T_{Jmax} (see [Table 6.5: Thermal characteristics on page 129](#)).
- In low-power dissipation state, T_A can be extended to this range as long as T_J does not exceed T_{Jmax} (see [Table 6.5: Thermal characteristics on page 129](#)).

Figure 16. Typical current consumption in Stop mode with regulator in low-power mode versus temperature at different V_{DD} values

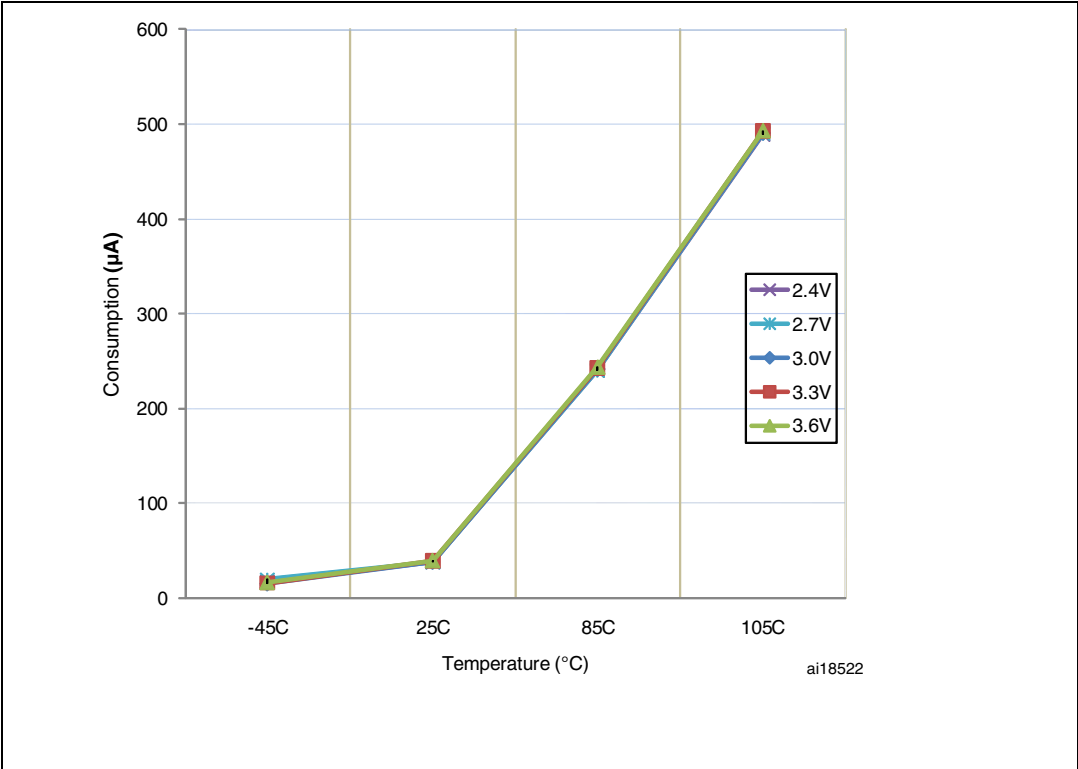


Figure 17. Typical current consumption in Standby mode versus temperature at different V_{DD} values

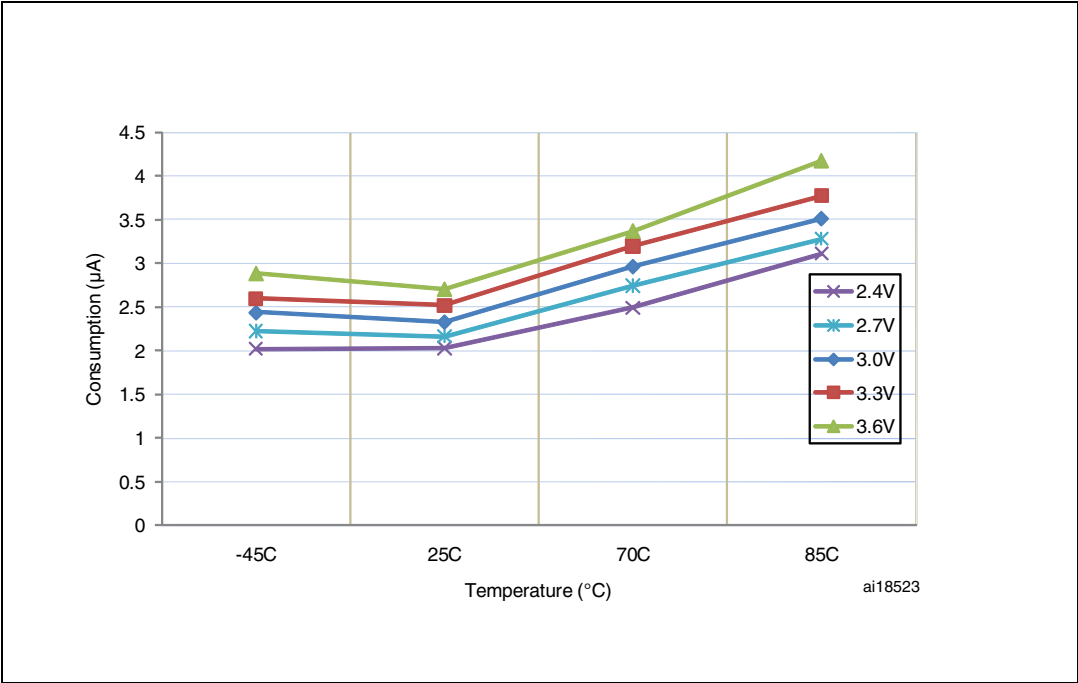


Figure 18. High-speed external clock source AC timing diagram

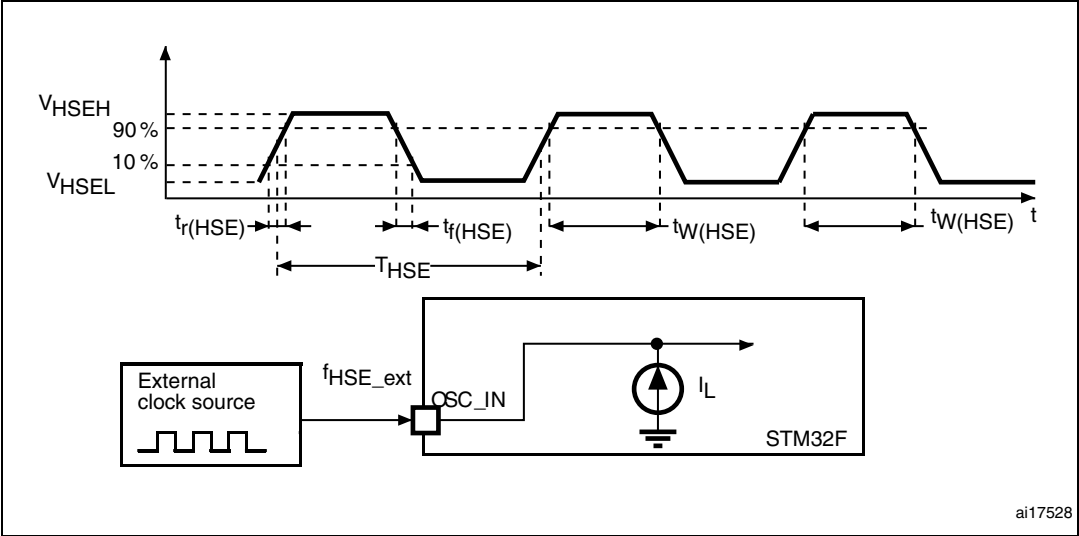


Figure 19. Low-speed external clock source AC timing diagram

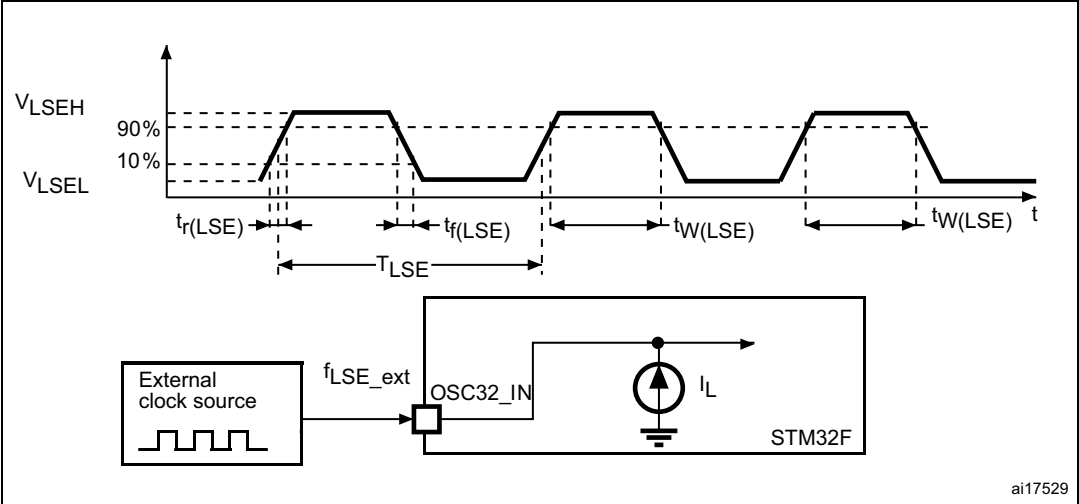


Figure 26. Synchronous multiplexed NOR/PSRAM read timings

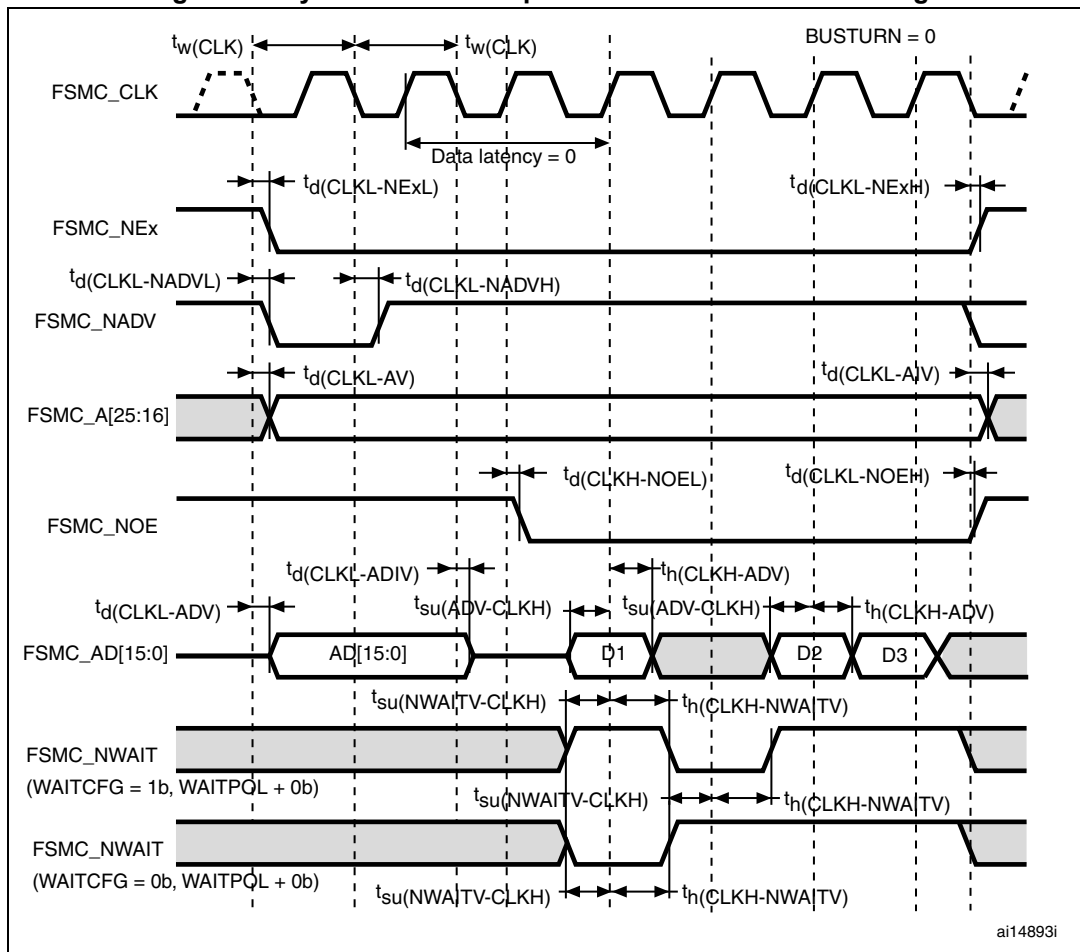
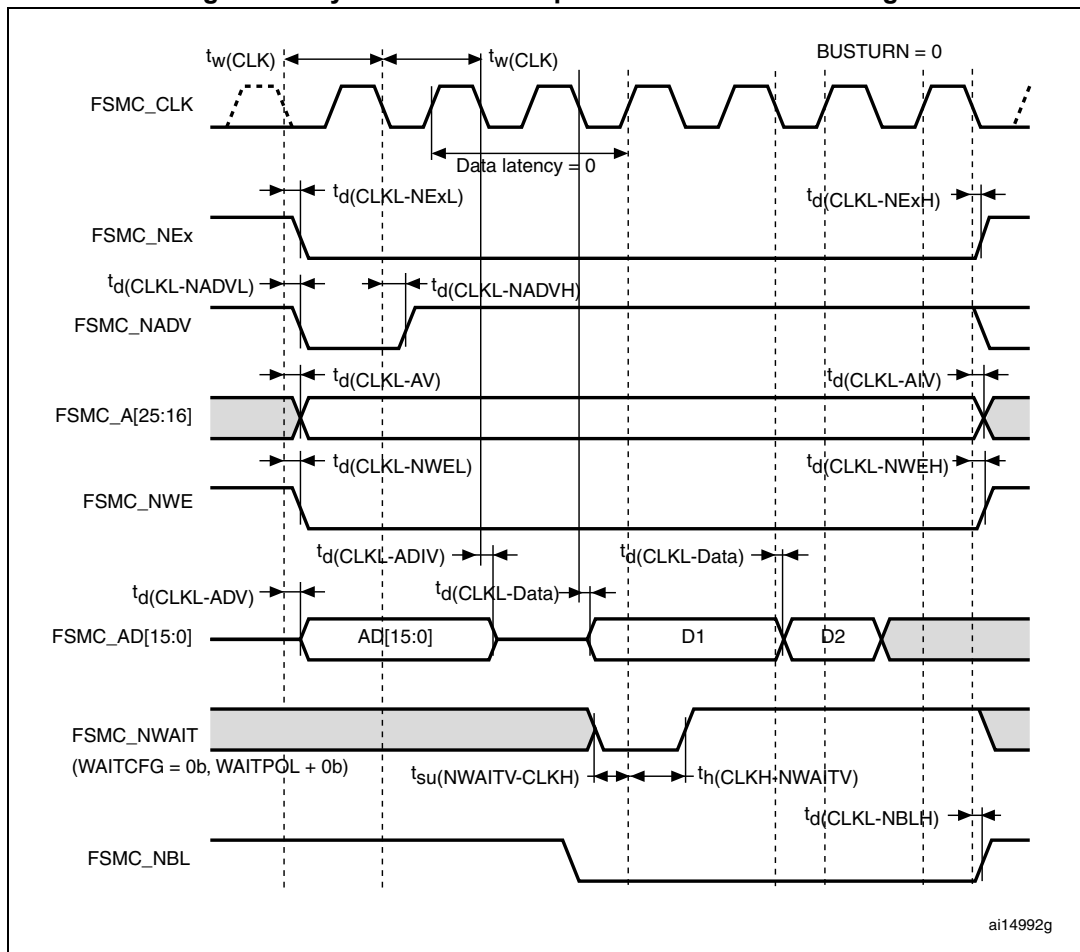


Figure 27. Synchronous multiplexed PSRAM write timings



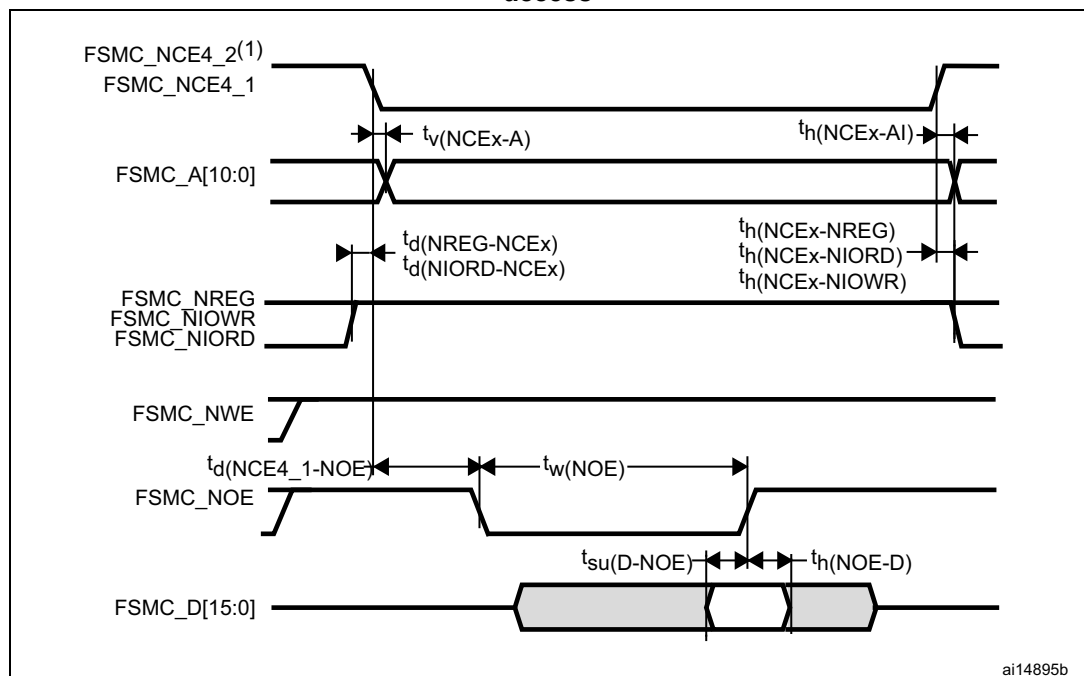
1. $C_L = 15$ pF.

PC Card/CompactFlash controller waveforms and timings

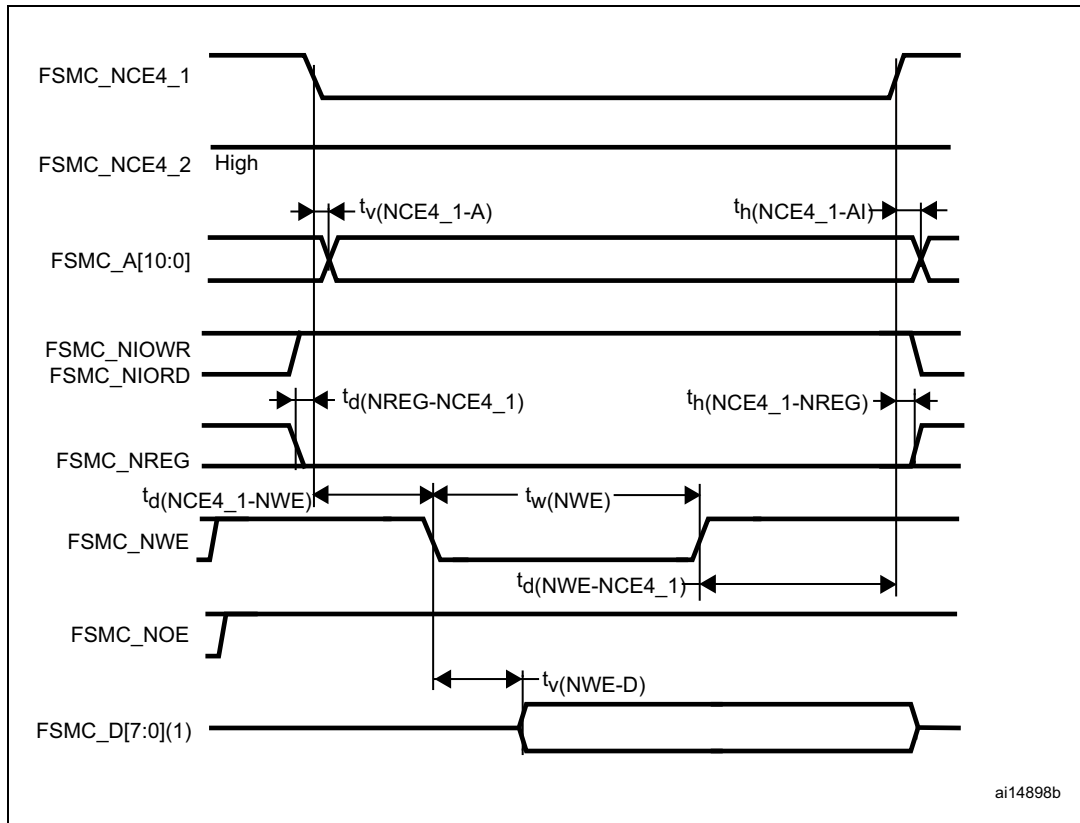
Figure 30 through Figure 35 represent synchronous waveforms and Table 42 provides the corresponding timings. The results shown in this table are obtained with the following FSMC configuration:

- COM.FSMC_SetupTime = 0x04;
- COM.FSMC_WaitSetupTime = 0x07;
- COM.FSMC_HoldSetupTime = 0x04;
- COM.FSMC_HiZSetupTime = 0x00;
- ATT.FSMC_SetupTime = 0x04;
- ATT.FSMC_WaitSetupTime = 0x07;
- ATT.FSMC_HoldSetupTime = 0x04;
- ATT.FSMC_HiZSetupTime = 0x00;
- IO.FSMC_SetupTime = 0x04;
- IO.FSMC_WaitSetupTime = 0x07;
- IO.FSMC_HoldSetupTime = 0x04;
- IO.FSMC_HiZSetupTime = 0x00;
- TCLRSetupTime = 0;
- TARSetupTime = 0;

Figure 30. PC Card/CompactFlash controller waveforms for common memory read access



1. FSMC_NCE4_2 remains high (inactive) during 8-bit access.

Figure 33. PC Card/CompactFlash controller waveforms for attribute memory write access

1. Only data bits 0...7 are driven (bits 8...15 remains HiZ).

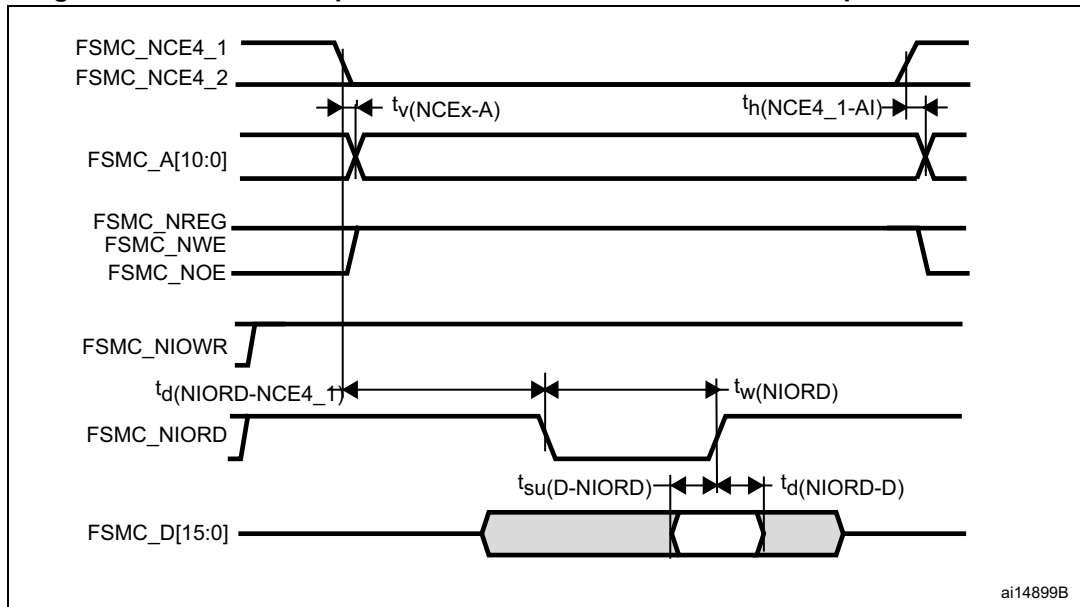
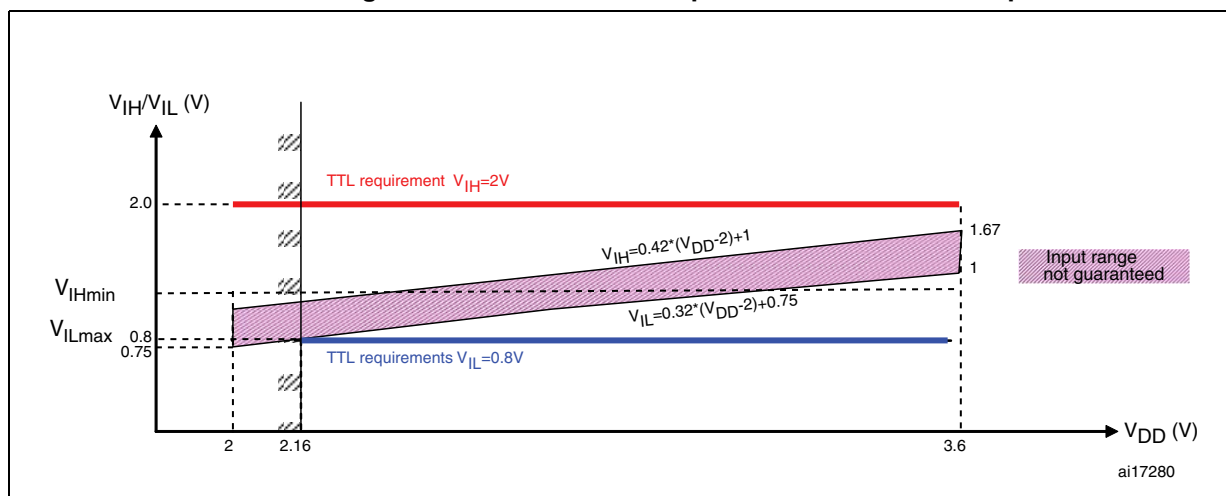
Figure 34. PC Card/CompactFlash controller waveforms for I/O space read access

Table 43. Switching characteristics for NAND Flash write cycles⁽¹⁾

Symbol	Parameter	Min	Max	Unit
$t_{w(NWE)}$	FSMC_NWE low width	$3t_{HCLK}$	$3t_{HCLK}$	ns
$t_{v(NWE-D)}$	FSMC_NWE low to FSMC_D[15:0] valid	-	0	ns
$t_{h(NWE-D)}$	FSMC_NWE high to FSMC_D[15:0] invalid	$2t_{HCLK} + 2$	-	ns
$t_{d(ALE-NWE)}$	FSMC_ALE valid before FSMC_NWE low	-	$3t_{HCLK} + 1.5$	ns
$t_{h(NWE-ALE)}$	FSMC_NWE high to FSMC_ALE invalid	$3t_{HCLK} + 8$	-	ns
$t_{d(ALE-NOE)}$	FSMC_ALE valid before FSMC_NOE low	-	$2t_{HCLK}$	ns
$t_{h(NO-E-ALE)}$	FSMC_NWE high to FSMC_ALE invalid	$2t_{HCLK}$	-	ns

1. $C_L = 15$ pF.

Figure 43. 5 V tolerant I/O input characteristics - TTL port



Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to ± 8 mA, and sink or source up to ± 20 mA (with a relaxed V_{OL}/V_{OH}) except PC13, PC14 and PC15 which can sink or source up to ± 3 mA. When using the GPIOs PC13 to PC15 in output mode, the speed should not exceed 2 MHz with a maximum load of 30 pF.

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in [Section 5.2](#):

- The sum of the currents sourced by all the I/Os on V_{DD} , plus the maximum Run consumption of the MCU sourced on V_{DD} , cannot exceed the absolute maximum rating I_{VDD} (see [Table 8](#)).
- The sum of the currents sunk by all the I/Os on V_{SS} plus the maximum Run consumption of the MCU sunk on V_{SS} cannot exceed the absolute maximum rating I_{VSS} (see [Table 8](#)).

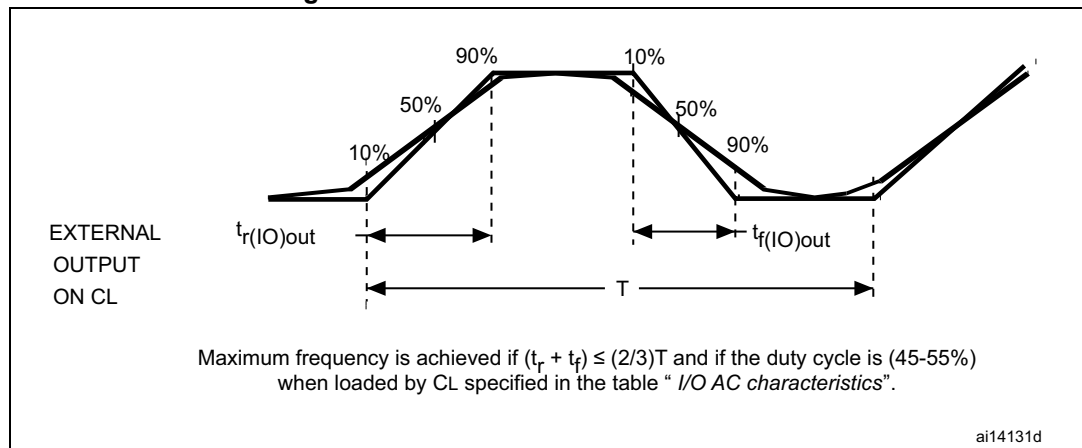
Output voltage levels

Unless otherwise specified, the parameters given in [Table 50](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 10](#). All I/Os are CMOS and TTL compliant.

Table 50. Output voltage characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin when 8 pins are sunk at same time	TTL port ⁽³⁾ $I_{IO} = +8$ mA $2.7\text{ V} < V_{DD} < 3.6\text{ V}$	-	0.4	V
$V_{OH}^{(2)}$	Output high level voltage for an I/O pin when 8 pins are sourced at same time		$V_{DD}-0.4$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin when 8 pins are sunk at same time	CMOS port ⁽³⁾ $I_{IO} = +8$ mA $2.7\text{ V} < V_{DD} < 3.6\text{ V}$	-	0.4	V
$V_{OH}^{(2)}$	Output high level voltage for an I/O pin when 8 pins are sourced at same time		2.4	-	

Figure 44. I/O AC characteristics definition



5.3.15 NRST pin characteristics

The NRST pin input driver uses CMOS technology. It is connected to a permanent pull-up resistor, R_{PU} (see [Table 49](#)).

Unless otherwise specified, the parameters given in [Table 52](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 10](#).

Table 52. NRST pin characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NRST)}^{(1)}$	NRST Input low level voltage	-	-0.5	-	0.8	V
$V_{IH(NRST)}^{(1)}$	NRST Input high level voltage	-	2	-	$V_{DD}+0.5$	
$V_{hys(NRST)}$	NRST Schmitt trigger voltage hysteresis	-	-	200	-	mV
R_{PU}	Weak pull-up equivalent resistor ⁽²⁾	$V_{IN} = V_{SS}$	30	40	50	k Ω
$V_{F(NRST)}^{(1)}$	NRST Input filtered pulse	-	-	-	100	ns
$V_{NF(NRST)}^{(1)}$	NRST Input not filtered pulse	-	300	-	-	ns

1. Guaranteed by design, not tested in production.

2. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance must be minimum (~10% order).

5.3.17 Communications interfaces

I²C interface characteristics

The STM32F103xF, STM32F103xD and STM32F103xGSTM32F103xF and STM32F103xG performance line I²C interface meets the requirements of the standard I²C communication protocol with the following restrictions: the I/O pins SDA and SCL are mapped to are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V_{DD} is disabled, but is still present.

The I²C characteristics are described in [Table 54](#). Refer also to [Section 5.3.14: I/O port characteristics](#) for more details on the input/output alternate function characteristics (SDA and SCL).

Table 54. I²C characteristics

Symbol	Parameter	Standard mode I ² C ⁽¹⁾⁽²⁾		Fast mode I ² C ⁽¹⁾⁽²⁾		Unit
		Min	Max	Min	Max	
t _w (SCLL)	SCL clock low time	4.7	-	1.3	-	μs
t _w (SCLH)	SCL clock high time	4.0	-	0.6	-	
t _{su} (SDA)	SDA setup time	250	-	100	-	ns
t _h (SDA)	SDA data hold time	-	3450 ⁽³⁾	-	900 ⁽³⁾	
t _r (SDA) t _r (SCL)	SDA and SCL rise time	-	1000	-	300	
t _f (SDA) t _f (SCL)	SDA and SCL fall time	-	300	-	300	
t _h (STA)	Start condition hold time	4.0	-	0.6	-	μs
t _{su} (STA)	Repeated Start condition setup time	4.7	-	0.6	-	
t _{su} (STO)	Stop condition setup time	4.0	-	0.6	-	μs
t _w (STO:STA)	Stop to Start condition time (bus free)	4.7	-	1.3	-	μs
C _b	Capacitive load for each bus line	-	400	-	400	pF
t _{SP}	Pulse width of the spikes that are suppressed by the analog filter for standard and fast mode	0	50 ⁽⁴⁾	0	50 ⁽⁴⁾	μs

1. Guaranteed by design, not tested in production.
2. f_{PCLK1} must be at least 2 MHz to achieve standard mode I²C frequencies. It must be at least 4 MHz to achieve the fast mode I²C frequencies and it must be a multiple of 10 MHz in order to reach the I²C fast mode maximum clock speed of 400 kHz.
3. The device must internally provide a hold time of at least 300ns for the SDA signal in order to bridge the undefined region on the falling edge of SCL.
4. The minimum width of the spikes filtered by the analog filter is above t_{SP}(max).

SD/SDIO MMC card host interface (SDIO) characteristics

Unless otherwise specified, the parameters given in [Table 58](#) are derived from tests performed under ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 10](#).

Refer to [Section 5.3.14: I/O port characteristics](#) for more details on the input/output alternate function characteristics (D[7:0], CMD, CK).

Figure 52. SDIO high-speed mode

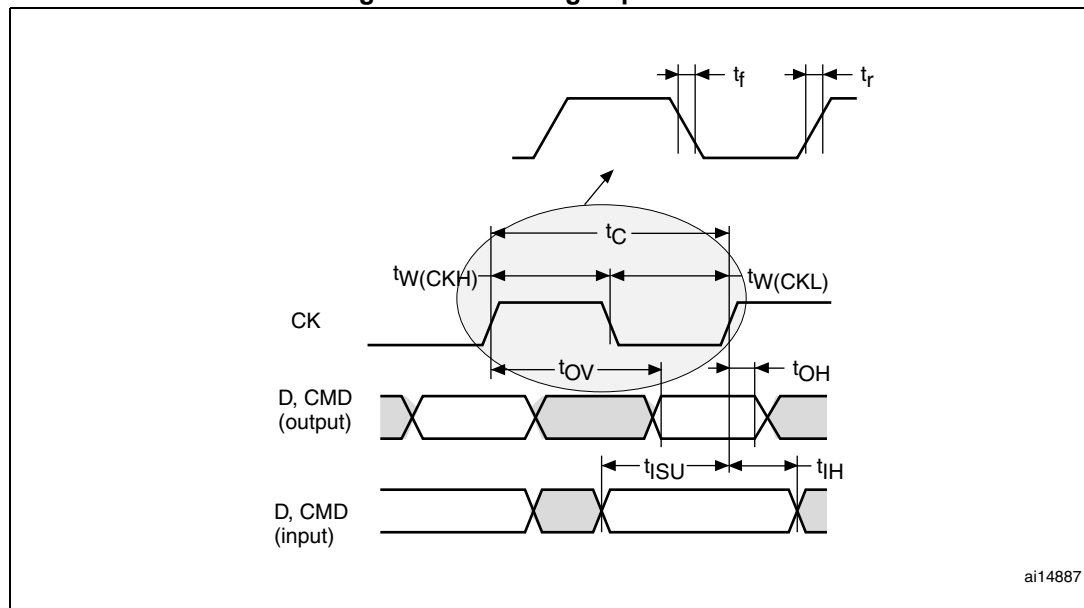


Figure 53. SD default mode

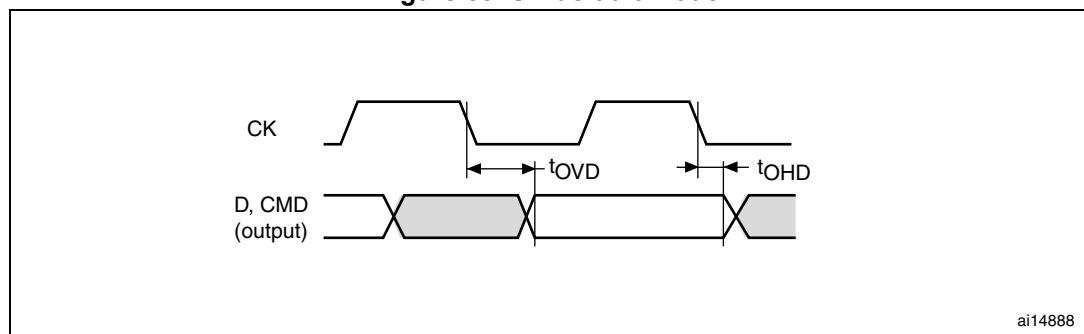


Table 58. SD / MMC characteristics

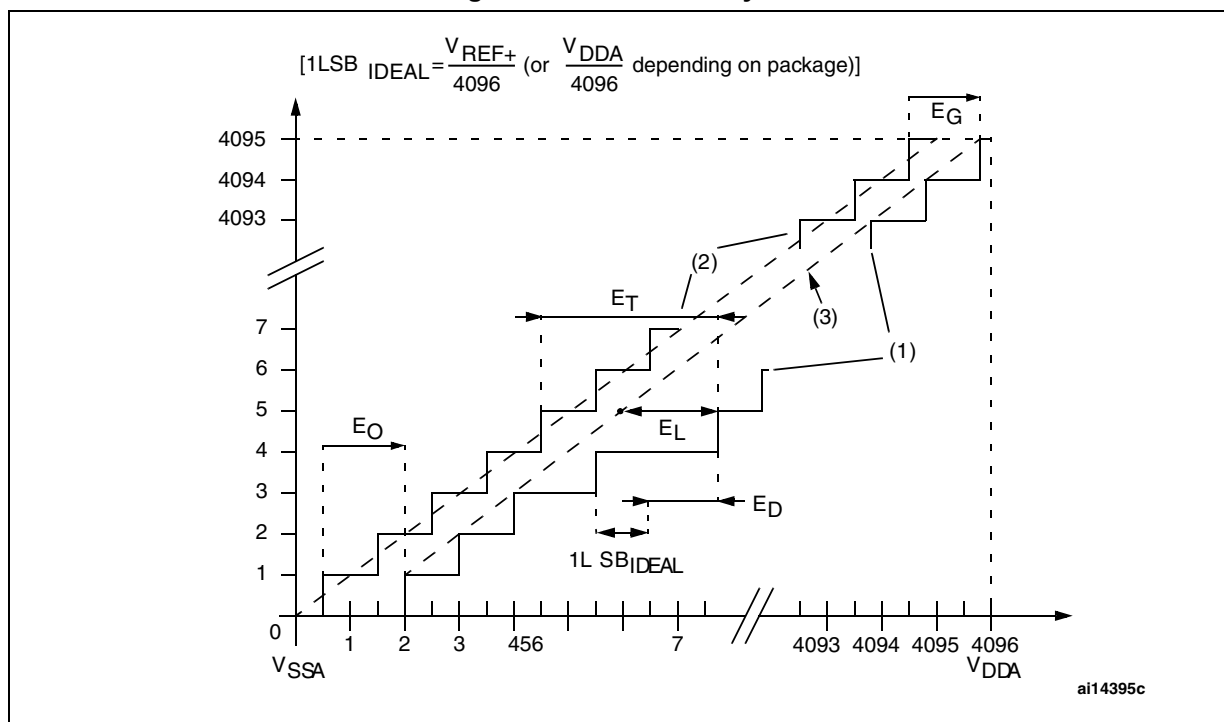
Symbol	Parameter	Conditions	Min	Max	Unit
f_{PP}	Clock frequency in data transfer mode	$C_L \leq 30 \text{ pF}$	0	48	MHz
$tW(CKL)$	Clock low time, $f_{PP} = 16 \text{ MHz}$	$C_L \leq 30 \text{ pF}$	32	-	ns
$tW(CKH)$	Clock high time, $f_{PP} = 16 \text{ MHz}$	$C_L \leq 30 \text{ pF}$	30	-	
t_r	Clock rise time	$C_L \leq 30 \text{ pF}$	-	4	
t_f	Clock fall time	$C_L \leq 30 \text{ pF}$	-	5	

Table 65. ADC accuracy^{(1) (2)(3)}

Symbol	Parameter	Test conditions	Typ	Max ⁽⁴⁾	Unit
ET	Total unadjusted error	f _{PCLK2} = 56 MHz, f _{ADC} = 14 MHz, R _{AIN} < 10 kΩ, V _{DDA} = 2.4 V to 3.6 V Measurements made after ADC calibration	±2	±5	LSB
EO	Offset error		±1.5	±2.5	
EG	Gain error		±1.5	±3	
ED	Differential linearity error		±1	±2	
EL	Integral linearity error		±1.5	±3	

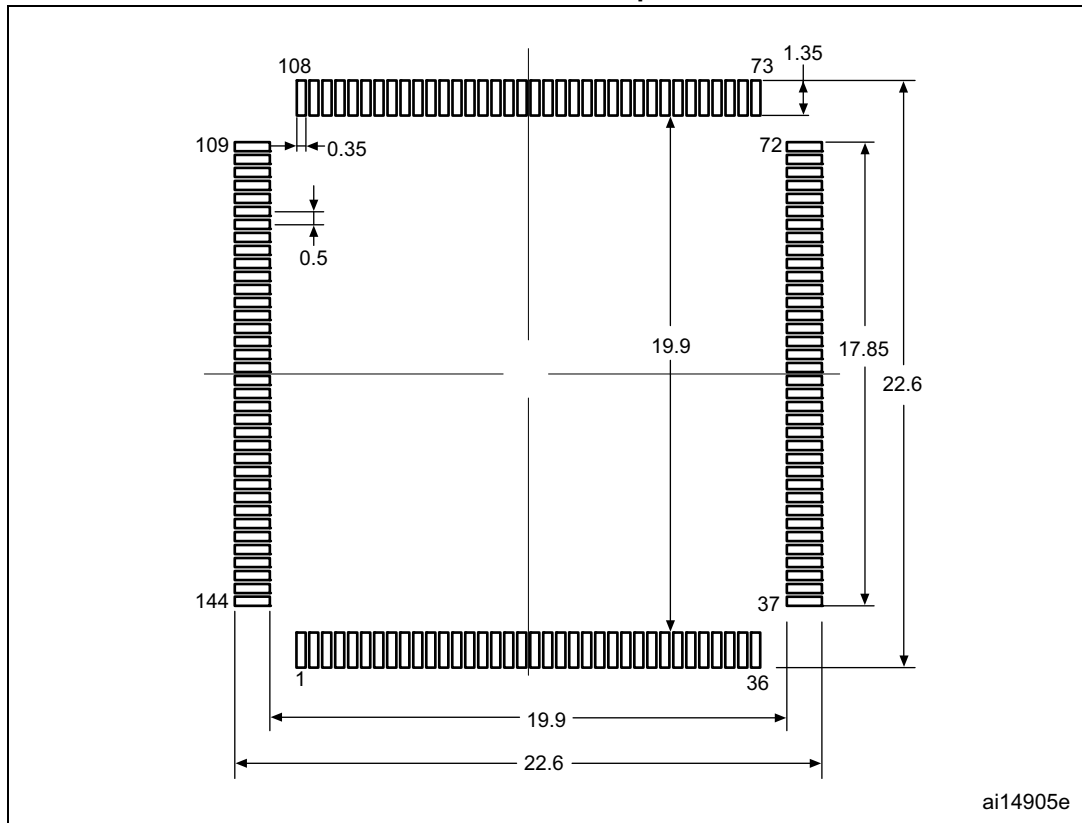
1. ADC DC accuracy values are measured after internal calibration.
2. Better performance could be achieved in restricted V_{DD}, frequency, V_{REF} and temperature ranges.
3. ADC Accuracy vs. Negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
Any positive injection current within the limits specified for I_{INJ(PIN)} and ΣI_{INJ(PIN)} in [Section 5.3.14](#) does not affect the ADC accuracy.
4. Preliminary values.

Figure 55. ADC accuracy characteristics



1. Example of an actual transfer curve.
2. Ideal transfer curve.
3. End point correlation line.
4. ET = Total Unadjusted Error: maximum deviation between the actual and the ideal transfer curves.
EO = Offset Error: deviation between the first actual transition and the first ideal one.
EG = Gain Error: deviation between the last ideal transition and the last actual one.
ED = Differential Linearity Error: maximum deviation between actual steps and the ideal one.
EL = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

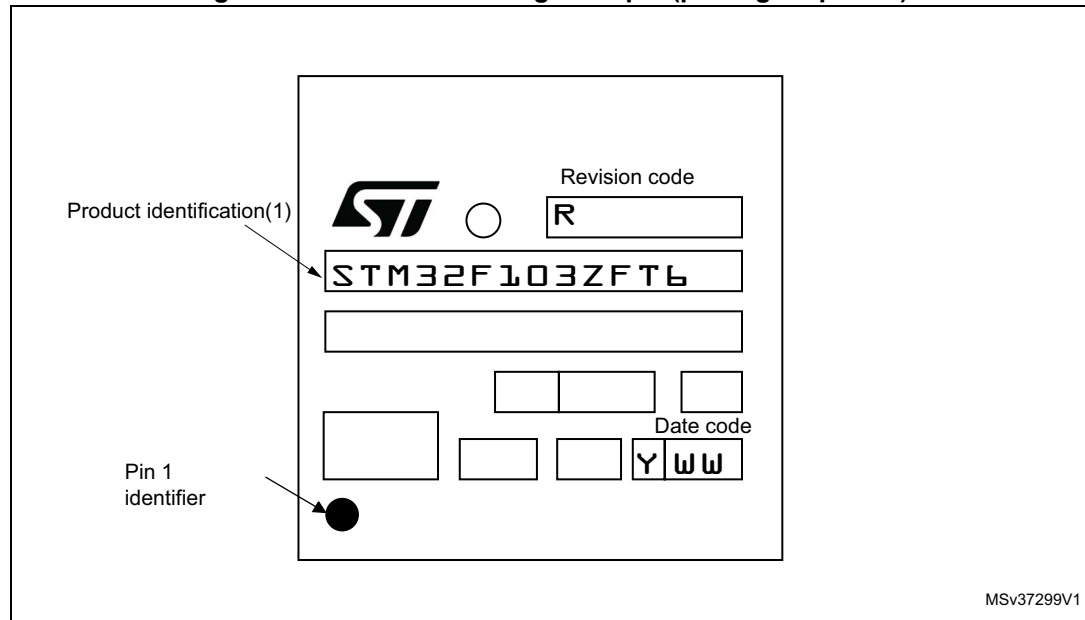
Figure 63. LQFP144 - 144-pin, 20 x 20 mm low-profile quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

Device marking for LQFP144 package

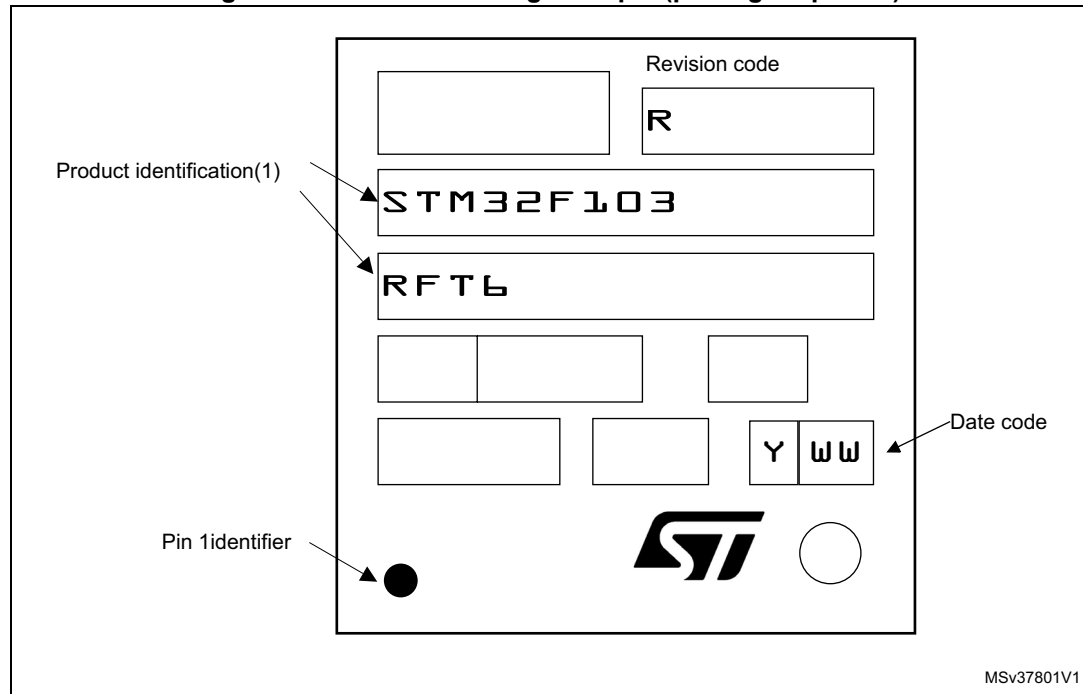
The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 64. LQFP144 marking example (package top view)

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

Device marking for LQFP64 package

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 70. LQFP64 marking example (package top view)

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

Using the values obtained in [Table 72](#) T_{Jmax} is calculated as follows:

– For LQFP100, 46 °C/W

$$T_{Jmax} = 115\text{ °C} + (46\text{ °C/W} \times 134\text{ mW}) = 115\text{ °C} + 6.2\text{ °C} = 121.2\text{ °C}$$

This is within the range of the suffix 7 version parts ($-40 < T_J < 125\text{ °C}$).

In this case, parts must be ordered at least with the temperature range suffix 7 (see [Section 7: Part numbering](#)).

Figure 71. LQFP100 P_D max vs. T_A

